## Preliminary Technical Data

## FEATURES

Specified for $V_{\text {DD }}$ of 2.7 V to 5.25 V
1.75MSPS for AD7470 (10-Bit)
1.5MSPS for AD7472 (12-Bit)

Low Power:
3mW typ at 1.75MSPS with 3V Supplies
9 mW typ at 1.75MSPS with 5V Supplies Wide Input Bandwidth:

70dB SNR at 500kHz Input Frequency
Flexible Power/Throughput Rate Management No Pipeline Delays
High Speed Parallel Interface
Shut Down Mode: 500nA typ.
24-Pin SOIC and TSSOP Packages

## GENERAL DESCRIPTION

The AD 7470/AD 7472 are 10-bit /12-bit high speed, low power, successive-approximation ADCs. The parts operate from a single 2.7 V to 5.25 V power supply and feature throughput rates up to 1.5M SPS for the 12-bit AD 7472 and up to 1.75 M SPS for the 10-bit AD 7470. The parts contain a low-noise, wide bandwidth track/hold amplifier which can handle input frequencies in excess of 1 MHz .
The conversion process and data acquisition are controlled using standard control inputs allowing easy interfacing to microprocessors or DSPs. T he input signal is sampled on the falling edge of CONVST and conversion is also initiated at this point. The BU SY goes high at the start of conversion and goes low 465 ns later to indicate that the conversion is complete. There are no pipelined delays associated with the part. The conversion result is accessed via standard $\overline{\mathrm{CS}}$ and $\overline{\mathrm{RD}}$ signals over a high speed parallel interface.
The AD 7470/AD 7472 uses advanced design techniques to achieve very low power dissipation at high throughput rates. With 3 V supplies and 1.75 M SPS throughput rate, the parts consume just 1 mA . With 5 V supplies and 1.75 M SPS , the current consumption is 1.8 mA . The part also offers flexible power/throughput rate management. Operating the part with 3 V supplies and 500 ksps throughput reduces the current consumption to 0.5 mA . At 5 V supplies and 500 ksps , the part consumes 0.8 mA .

It is also possible to operate the parts in an auto shutdown mode, where the part powers up to do a conversion and automatically enters shutdown mode at the end of conversion.

## REV. PrD 09/98

FUNCTIONAL BLOCK DIAGRAM


AD 7470 is a 10 Bit part with DB0 to DB9 as outputs
AD7472 is a 12 Bit part with DB0 to DB11 as outputs
$U$ sing this method allows very low power dissipation numbers at lower throughput rates. In this mode, the parts can be operated with 3 V supplies at 100 ksps , and consume an average current of just 150 uA . At 5 V supplies and 100 ksps , the average current consumption is 270uA.
The analog input range for the part is 0 to REF IN. The +2.5 V reference is applied externally to the REF IN pin. The conversion rate is determined by the externally-applied clock.

## PRODUCT HIGHLIGHTS

1.H igh Throughput with L ow Power Consumption the AD 7470 offers 1.75 M SPS throughput and the AD 7472 offers 1.5M SPS throughput rates with 3 mW power consumption.
2. Flexible Power/T hroughput Rate M anagement The conversion rate is determined by an externally-applied clock allowing the power to be reduced as the conversion rate is reduced. The part also features an autoshutdown mode to maximize power efficiency at lower throughput rates.
3. No Pipeline Delay.

The part features a standard successive-approximation ADC with accurate control of the sampling instant via a CONVST input and once off conversion control.

[^0] $\mathrm{T}_{A}=\mathrm{T}_{\text {MIN }}$ to $\mathrm{T}_{\text {MAx, }}$ unless otherwise noted.)

| Parameter | A Version ${ }^{1}$ | Units | Test Conditions/Comments |
| :---: | :---: | :---: | :---: |
| DYNAMIC PERFORMANCE <br> Signal to Noise + Distortion (SINAD) ${ }^{2}$ <br> Signal to $N$ oise Ratio (SNR) ${ }^{2}$ <br> Total Harmonic Distortion (THD) <br> Peak H armonic or Spurious N oise (SF DR) <br> Intermodulation Distortion (IM D) <br> Second Order T erms <br> Third Order T erms <br> A perture D elay <br> A perture Jitter <br> Full Power Bandwidth | $\begin{aligned} & 58 \\ & 59 \\ & -70 \\ & -70 \\ & \\ & -75 \\ & -75 \\ & \text { tbd } \\ & \text { tbd } \\ & 20 \end{aligned}$ | dB min $d B \min$ dB max dB max <br> dB typ dB typ ns typ ns typ M Hz typ | $\mathrm{f}_{\mathrm{IN}}=500 \mathrm{kH} z$ Sine W ave, $\mathrm{f}_{\mathrm{S}}=1.75 \mathrm{M}$ sps <br> $\mathrm{f}_{\mathrm{IN}}=500 \mathrm{kHz}$ Sine W ave, $\mathrm{f}_{\mathrm{S}}=1.75 \mathrm{M} \mathrm{sps}$ <br> $\mathrm{f}_{\mathrm{IN}}=500 \mathrm{kH} z$ Sine W ave, $\mathrm{f}_{\mathrm{S}}=1.75 \mathrm{M}$ sps <br> $\mathrm{f}_{\mathrm{IN}}=500 \mathrm{kHz}$ Sine W ave, $\mathrm{f}_{\mathrm{S}}=1.75 \mathrm{M} \mathrm{sps}$ |
| DC ACCURACY <br> Resolution <br> Integral N onlinearity Differential N onlinearity <br> Offset Error <br> Gain Error | $\begin{aligned} & 10 \\ & \pm 1 \\ & \pm 0.9 \\ & \pm 1 \\ & \pm 1 \end{aligned}$ | Bits <br> LSB max <br> LSB max <br> LSB max <br> LSB max | Guaranteed No M issed Codes to 10 Bits. |
| ANALOG INPUT Input Voltage Ranges dc Leakage Current Input C apacitance | 0 to REF IN <br> $\pm 1$ <br> 20 | Volts <br> UA max pF typ |  |
| REFERENCE INPUT <br> REF IN Input Voltage Range dc Leakage C urrent Input C apacitance | $\begin{aligned} & 2.5 \\ & \pm 1 \\ & 20 \end{aligned}$ | V <br> $\mu \mathrm{A} \max$ <br> pF typ | +/-1\% for Specified Performance |
| LOGIC INPUTS <br> Input High Voltage, $\mathrm{V}_{\text {INH }}$ <br> Input Low Voltage, $\mathrm{V}_{\text {INL }}$ <br> Input Current, $\mathrm{I}_{\mathrm{IN}}$ <br> Input C apacitance, $\mathrm{C}_{1 \mathrm{~N}}{ }^{3}$ | $(V d d=5)$ $(V d d=3)$ <br> 2.8 2.4 <br> 0.4 0.4 <br> $\pm 1$ $\pm 1$ <br> 10 10 | Volts <br> $V$ min <br> $\checkmark$ max <br> $\mu \mathrm{A}$ max <br> pF max | Typically $10 \mathrm{nA}, \mathrm{V}_{\text {IN }}=0 \mathrm{~V}$ or $\mathrm{V}_{\text {D }}$ |
| LOGIC OUTPUTS <br> Output High Voltage, $\mathrm{V}_{\mathrm{OH}}$ Output Low Voltage, $\mathrm{V}_{\text {OL }}$ Floating-State Leakage C urrent F loating-State O utput C apacitance Output Coding | $\begin{aligned} & \text { V DRIVE }-0.2 \\ & 0.4 \\ & \pm 10 \\ & 10 \\ & \text { Straight(N atural) } \\ & \text { Binary } \end{aligned}$ | $V$ min <br> $V$ max <br> $\mu \mathrm{A}$ max pF max | $\begin{aligned} & I_{\text {SOURCE }}=200 \mu \mathrm{~A} \\ & I_{\text {SINK }}=200 \mathrm{~mA} \\ & V_{\text {DD }}=2.7 \mathrm{~V} \text { to } 5.25 \mathrm{~V} \end{aligned}$ |
| CONVERSION RATE <br> Conversion Time Track/H old Acquisition Time Throughput Rate | $\begin{aligned} & 12 \\ & 100 \\ & 1.75 \end{aligned}$ | CLK IN cycles ns max M SPS max | 428ns with CLK IN at 28 M Hz <br> C onversion Time + Acquisition Time. <br> CLK IN at 28 MHz | $T_{A}=T_{\text {MIN }}$ to $T_{\text {MAX }}$ unless otherwise noted.)


| Parameter | A Version | Units | Test Conditions/Comments |
| :---: | :---: | :---: | :---: |
| POWER REQUIREMENTS |  |  |  |
| $\mathrm{V}_{\text {DD }}$ | +2.7/+5.25 | $V \min / \max$ |  |
| $\mathrm{I}_{\mathrm{DD}}{ }^{4}$ |  |  | Digital I/Ps $=0 \mathrm{~V}$ or DV DD |
| N ormal M ode | 2.2 | $m A \max$ | Typically 1.8 mA . |
|  |  |  | $\mathrm{V}_{\mathrm{DD}}=4.75 \mathrm{~V}$ to $5.25 \mathrm{~V} . \mathrm{f}_{\mathrm{S}}=1.75 \mathrm{M} \mathrm{SPS}$ |
| N ormal M ode | 1.33 | $m A \max$ | T ypically 1 mA . |
|  |  |  | $\mathrm{V}_{\mathrm{DD}}=2.7 \mathrm{~V}$ to 3.3V. $\mathrm{f}_{\mathrm{S}}=1.75 \mathrm{M}$ SPS |
| Shutdown M ode | 1 | $\mu \mathrm{A} \max$ | CLK IN $=0 \mathrm{~V}$ or DV ${ }_{\text {DD }}$ |
| Power Dissipation ${ }^{4}$ |  |  | Digital I/Ps $=0 \mathrm{~V}$ or $\mathrm{DV}^{\text {D }}$ |
| N ormal M ode | 11 | mW max | $V_{D D}=5 \mathrm{~V}$. |
|  | 4 | mW max | $V_{D D}=3 \mathrm{~V}$ |
| Shutdown M ode | 5 3 | uW max $\mu \mathrm{W}$ max | $\begin{aligned} & V_{D D}=5 \mathrm{~V} \cdot C L K \text { IN }=0 \mathrm{~V} \text { or } D V_{D D} \\ & V_{D D}=3 \mathrm{~V} . C L K \text { IN }=0 \mathrm{~V} \text { or } D V_{D D} \end{aligned}$ |

## NOTES

${ }^{1}$ Temperature ranges as follows: $\mathrm{A}, \mathrm{B}$ Versions: $-40^{\circ} \mathrm{C}$ to $+85^{\circ} \mathrm{C}$.
${ }^{2}$ SNR calculation includes distortion and noise components.
${ }^{3}$ Sample tested @ $+25^{\circ} \mathrm{C}$ to ensure compliance.
${ }^{4}$ See POWER VERSUS THROUGHPUT RATE section.
Specifications subject to change without notice.

## AD7472- SPECIFICATIONS ${ }^{1}$ <br> $\left(V_{D D}=+2.7 \mathrm{~V}\right.$ to +5.25 V , REF IN $=2.5 \mathrm{~V}, \mathrm{f}_{\text {CIKIN }}=28 \mathrm{MHz}$ unless otherwise noted; $\mathrm{T}_{A}=\mathrm{T}_{\text {MIN }}$ to $\mathrm{T}_{\text {MAx, }}$ unless otherwise noted.)

| Parameter | A Version ${ }^{1}$ | Units | Test Conditions/Comments |
| :---: | :---: | :---: | :---: |
| DYNAMIC PERFORMANCE <br> Signal to Noise + Distortion (SINAD) ${ }^{2}$ <br> Signal to Noise Ratio (SNR) ${ }^{2}$ <br> Total Harmonic Distortion (THD) <br> Peak Harmonic or Spurious N oise (SF DR) <br> Intermodulation Distortion (IM D) <br> Second Order Terms <br> Third Order Terms <br> Aperture Delay <br> A perture Jitter <br> Full Power Bandwidth | $\begin{aligned} & 69 \\ & 70 \\ & -76 \\ & -76 \\ & -78 \\ & -78 \\ & -78 \\ & \text { tbd } \\ & \text { tbd } \\ & 20 \end{aligned}$ | dB min <br> dB min <br> dB max <br> dB max <br> dB typ <br> dB typ <br> ns typ <br> ns typ <br> M Hz typ | $\mathrm{f}_{\mathrm{IN}}=500 \mathrm{kH} z$ Sine W ave, $\mathrm{f}_{\mathrm{S}}=1.5 \mathrm{M}$ sps $\mathrm{f}_{\mathrm{fN}}=500 \mathrm{kH} z$ Sine W ave, $\mathrm{f}_{\mathrm{S}}=1.5 \mathrm{M}$ sps $\mathrm{f}_{\mathrm{fN}}=500 \mathrm{kH}$ z Sine Wave, $\mathrm{f}_{\mathrm{S}}=1.5 \mathrm{M}$ sps $\mathrm{f}_{\mathrm{IN}}=500 \mathrm{kH}$ z Sine W ave, $\mathrm{f}_{\mathrm{S}}=1.5 \mathrm{M}$ sps |
| DC ACCURACY <br> Resolution <br> Integral N onlinearity Differential Nonlinearity Offset E rror Gain Error | $\begin{aligned} & 12 \\ & \pm 1 \\ & \pm 0.9 \\ & \pm 3 \\ & \pm 3 \end{aligned}$ | Bits <br> LSB max <br> LSB max <br> LSB max <br> LSB max | Guaranteed No M issed Codes to 12 Bits. |
| ANALOG INPUT Input Voltage Ranges dc Leakage C urrent Input Capacitance | $\begin{aligned} & 0 \text { to REF IN } \\ & \pm 1 \\ & 20 \end{aligned}$ | Volts $\mu \mathrm{A}$ max pF typ |  |
| REFERENCEINPUT <br> REF IN Input Voltage Range dc Leakage C urrent Input Capacitance | $\begin{aligned} & 2.5 \\ & \pm 1 \\ & 20 \end{aligned}$ | V $\mu \mathrm{A}$ max pF typ | +/-1\% for Specified Performance |
| LOGIC INPUTS Input High Voltage, $\mathrm{V}_{\text {INH }}$ Input Low Voltage, Vinl Input Current, $\mathrm{I}_{\text {IN }}$ Input Capacitance, $\mathrm{C}_{1 \mathrm{~N}}{ }^{3}$ | $(\mathrm{Vdd}=5)$ $(\mathrm{Vdd}=3)$ <br> 2.8 2.4 <br> 0.4 0.4 <br> $\pm 1$ $\pm 1$ <br> 10 10 | Volts <br> $V$ min <br> $\checkmark$ max <br> $\mu \mathrm{A}$ max <br> pF max | T ypically $10 \mathrm{nA}, \mathrm{V}_{\text {IN }}=0 \mathrm{~V}$ or $\mathrm{V}_{\mathrm{DD}}$ |
| LOGIC OUTPUTS <br> Output High Voltage, $\mathrm{V}_{\mathrm{OH}}$ <br> Output Low Voltage, VoL <br> Floating-State Leakage Current Floating-State Output Capacitance Output Coding | $\begin{aligned} & \text { V }_{\text {DRIVE }}-0.2 \\ & 0.4 \\ & \pm 10 \\ & 10 \\ & \text { Straight(N atural) } \\ & \text { Binary } \end{aligned}$ | $V$ min $V$ max $\mu \mathrm{A}$ max pF max | $I_{\text {source }}=200 \mu \mathrm{~A}$ <br> $\mathrm{I}_{\mathrm{SINK}}=200 \mathrm{~mA}$ <br> $\mathrm{V}_{\mathrm{DD}}=2.7 \mathrm{~V}$ to 5.25 V |
| CONVERSION RATE <br> Conversion Time Track/H old Acquisition Time Throughput Rate | $\begin{aligned} & 14 \\ & 100 \\ & 1.5 \end{aligned}$ | CLK IN cycles ns max MSPS max | 500 ns with CLK IN at 28 M Hz <br> Conversion Time + Acquisition Time. CLK IN at 28 M Hz | $T_{A}=T_{\text {MIN }}$ to $T_{\text {MAx, }}$ unless otherwise noted.)


| Parameter | A Version | Units | Test Conditions/Comments |
| :---: | :---: | :---: | :---: |
| POWER REQUIREMENTS |  |  |  |
| $V_{\text {DD }}$ | +2.7/+5.25 | $\checkmark \min /$ max |  |
| $\mathrm{I}_{\mathrm{DD}}{ }^{4}$ |  |  | Digital I/Ps $=0 \mathrm{~V}$ or DV ${ }_{\text {D }}$ |
| N ormal M ode | 2.2 | mA max | T ypically 1.8 mA . |
|  |  |  | $\mathrm{V}_{\mathrm{DD}}=4.75 \mathrm{~V}$ to $5.25 \mathrm{~V} . \mathrm{f}_{\mathrm{S}}=1.5 \mathrm{M} \mathrm{SPS}$ |
| N ormal M ode | 1.33 | mA max | T ypically 1mA. |
|  |  |  | $\mathrm{V}_{\mathrm{DD}}=2.7 \mathrm{~V}$ to 3.3V. $\mathrm{f}_{\mathrm{S}}=1.5 \mathrm{M} \mathrm{SPS}$ |
|  | 1 | uA max | CLK IN $=0 \mathrm{~V}$ or $\mathrm{DV}_{D D}$ |
| Power Dissipation ${ }^{4}$ |  |  | Digital I/Ps $=0 V$ or $D V_{D D}$ |
| N ormal M ode | 11 | mW max | $V_{D D}=5 \mathrm{~V}$. |
|  | 4 | mW max | $V_{D D}=3 \mathrm{~V}$ |
| Shutdown M ode | 5 | uW max | $\mathrm{V}_{\mathrm{DD}}=5 \mathrm{~V} . C L K$ IN $=0 \mathrm{~V}$ or $\mathrm{DV} \mathrm{V}_{\text {D }}$ |
|  | 3 | uW max | $\mathrm{V}_{\mathrm{DD}}=3 \mathrm{~V}$. CLK IN $=0 \mathrm{~V}$ or $\mathrm{DV}^{\text {D }}$ |

NOTES
${ }^{1} \mathrm{~T}$ emperature ranges as follows: $\mathrm{A}, \mathrm{B}$ Versions: $-40^{\circ} \mathrm{C}$ to $+85^{\circ} \mathrm{C}$.
${ }^{2}$ SNR calculation includes distortion and noise components.
${ }^{3}$ Sample tested @ $+25^{\circ} \mathrm{C}$ to ensure compliance.
${ }^{4}$ See POWER VERSUS THROUGHPUT RATE section.
Specifications subject to change without notice.


| Parameter | Limit at $\mathrm{T}_{\text {MIN }}, \mathrm{T}_{\text {MAX }}$ |  | Units | Description |
| :---: | :---: | :---: | :---: | :---: |
| $\mathrm{f}_{\text {CLK }}{ }^{2}$ | 1 | 1 | kHz min |  |
|  | 28 | 28 | M Hz max |  |
| $\mathrm{t}_{\text {Convert }}$ | $12 * \mathrm{t}_{\text {CLK }}$ | $14^{*} \mathrm{t}_{\text {CLK }}$ |  | $\mathrm{t}_{\text {CLK }}=1 / \mathrm{f}_{\text {CLK }}{ }_{\text {IN }}$ |
|  | 428 | 500 | ns max | $\mathrm{f}_{\text {CLK IN }}=28 \mathrm{M} \mathrm{Hz}$ |
| $t_{\text {WAKEUP }}$ | 1 | 1 | us max | W akeup T ime |
| $\mathrm{tacq}_{\text {aca }}$ | 100 | 100 | ns max | Acquisition T ime |
| $\mathrm{t}_{1}$ | 15 | 15 | $n \mathrm{nmin}$ | CONVST Pulse Width |
| $\mathrm{t}_{2}$ | 10 | 10 | ns min | CONVST to BUSY D elay |
| $t_{3}$ | 0 | 0 | ns max | BUSY to $\overline{\mathrm{CS}}$ Setup Time |
| $\mathrm{t}_{4}{ }^{3}$ | 0 | 0 | ns max | $\overline{\mathrm{CS}}$ to $\overline{\mathrm{RD}}$ Setup Time |
| $t_{5}$ | 30 | 30 | ns min | $\overline{\mathrm{RD}}$ Pulse Width |
| $\mathrm{t}_{6}{ }^{4}$ | 25 | 25 | $n \mathrm{nmin}$ | D ata Access Time After Falling Edge of $\overline{\mathrm{RD}}$ |
| $\mathrm{t}_{7}{ }^{5}$ | 5 | 5 | $n \mathrm{n}$ min | Bus Relinquish Time After Rising Edge of $\overline{\mathrm{RD}}$ |
| $\mathrm{t}_{8}$ | 0 | 0 | ns max | $\overline{\mathrm{CS}}$ to $\overline{\mathrm{RD}} \mathrm{H}$ old Time |

NOTES
${ }^{1}$ Sample tested at $+25^{\circ} \mathrm{C}$ to ensure compliance. All input signals are specified with $\mathrm{tr}=\mathrm{tf}=5 \mathrm{~ns}\left(10 \%\right.$ to $90 \%$ of $\left.\mathrm{V}_{\mathrm{DD}}\right)$ and timed from a voltage level of 1.6 Volts. See Figure 2.
${ }^{2} \mathrm{M}$ ark/Space ratio for the CLK input is $40 / 60$ to $60 / 40$.
${ }^{3} \mathrm{M}$ easured with the load circuit of Figure 1 and defined as the time required for the output to cross 0.8 V or 2.0 V .
${ }^{4} \mathrm{t}_{7}$ is derived form the measured time taken by the data outputs to change 0.5 V when loaded with the circuit of Figure 1 . The measured number is then extrapolated back to remove the effects of charging or discharging the 50 pF capacitor. This means that the time, $\mathrm{t}_{7}$, quoted in the timing characteristics is the true bus relinquish time of the part and is independent of the bus loading.
Specifications subject to change without notice.


Figure 1. Load Circuit for Digital Output Timing Specifications


Figure 2. AD7470/AD7472 Timing Diagram

## Preliminary Technical Data



Figure 3. AD7470/AD7472 Wake-Up Timing Diagram (Burst Clock)
ABSOLUTE MAXIMUM RATINGS ${ }^{1}$
( $\mathrm{T}_{\mathrm{A}}=+25^{\circ} \mathrm{C}$ unless otherwise noted)
$A V_{D D}$ to $A G N D / D G N D$ ..... -0.3 V to +7 V
$D V_{D D}$ to $A G N D / D G N D$ -0.3 V to +7 V
V Drive to $A G N D / D G N D$ -0.3 V to +7 V
$A V_{D D}$ to $D V_{D D}$ -0.3 V to +0.3 V
$V_{\text {drive }}$ to DV -0.3 V to +0.3 V
AGND TO DGND -0.3 V to +0.3 V
Analog Input Voltage to AGND

$\qquad$
-0.3 V to AVDD +0.3 V
Digital Input Voltage to DGND -0.3V to DVDD+0.3V
REF IN to AGND

$\qquad$
-0.3 V to AVDD+0.3V
$e^{2}$
$\qquad$ $\pm 10 \mathrm{~mA}$Operating Temperature Range
Commercial (A Version)

$\qquad$
$-40^{\circ} \mathrm{C}$ to $+85^{\circ} \mathrm{C}$
Storage Temperature Range

$\qquad$
$-65^{\circ} \mathrm{C}$ to $+150^{\circ} \mathrm{C}$
Junction Temperature ..... $+150^{\circ} \mathrm{C}$
SOIC, TSSOP Package Dissipation ..... +450mW
$\theta_{\mathrm{JA}}$ Thermal Impedance ... $75^{\circ} \mathrm{C} / \mathrm{W}$ (SOIC) $115^{\circ} \mathrm{C} / \mathrm{W}$ (TSSOP)$\theta_{\mathrm{Jc}}$ T hermal Impedance ..... $25^{\circ} \mathrm{C} / \mathrm{W}$ (SOIC) $35^{\circ} \mathrm{C} / \mathrm{W}$ (T SSOP)Lead Temperature, Soldering
Vapor Phase (60 secs) ..... $+215^{\circ} \mathrm{C}$
Infared (15 secs) ..... $+220^{\circ} \mathrm{C}$

NOTES
${ }^{1}$ Stresses above those listed under "Absolute M aximum Ratings" may cause permanent damage to the device. This is a stress rating only and functional operation of the device at these or any other conditions above those listed in the operational sections of this specification is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.
${ }^{2}$ Transient currents of up to 100 mA will not cause SCR latch up.

ORDERING GUIDE

| Model | Range | Resolution (Bits) | Package Option ${ }^{1}$ | Branding |
| :---: | :---: | :---: | :---: | :---: |
| AD 7470ARU | $-40^{\circ} \mathrm{C}$ to $+85^{\circ} \mathrm{C}$ | 10 | RU-24 |  |
| AD 7472AR | $-40^{\circ} \mathrm{C}$ to $+85^{\circ} \mathrm{C}$ | 12 | R-24 |  |
| AD 7472ARU | $-40^{\circ} \mathrm{C}$ to $+85^{\circ} \mathrm{C}$ | 12 | RU-24 |  |
| $\begin{aligned} & \text { EVAL-AD } 7470 C^{2} \\ & \text { EVAL-AD } 7472 C B^{2} \\ & \text { EVAL-CONTROL BOARD } \end{aligned}$ | Evaluation Board Evaluation Board Controller Board |  |  |  |
| $\begin{aligned} & \text { NOTES } \\ & 1^{1} \text { = SOIC; RU = TSSOP. } \end{aligned}$ |  |  |  |  |
| ${ }^{2}$ This can be used as a stand-alone evaluation board or in conjunction with the EVAL-CONTROL BOARD for evaluation/ demonstration purposes. |  |  |  |  |

## CAUTION

ESD (electrostatic discharge) sensitive device. Electrostatic charges as high as 4000 V readily accumulate on the human body and test equipment and can discharge without detection. Although the XX 0000 features proprietary ESD protection circuitry, permanent damage may occur on devices subjected to high energy electrostatic discharges. Therefore, proper ESD precautions are recommended to avoid performance degradation or loss of functionality.

## AD7470 PIN CONFIGURATION



NC = NO CONNECT


## PIN FUNCTION DESCRIPTION

| Pin <br> Mnemonic | Function |
| :---: | :---: |
| $\overline{\mathrm{CS}}$ | Chip Select. Active low logic input used in conjunction with $\overline{\mathrm{RD}}$ to access the conversion result. The conversion result is placed on the data bus following the falling edge of both $\overline{\mathrm{CS}}$ and $\overline{\mathrm{RD}} . \overline{\mathrm{CS}}$ and $\overline{\mathrm{RD}}$ are both connected to the same AND gate on the input so the signals are interchangeable. $\overline{\mathrm{CS}}$ can be hardwired permantly low. |
| $\overline{\mathrm{RD}}$ | Read Input. Logic Input used in conjunction with $\overline{\mathrm{CS}}$ to access the conversion result. The conversion result is placed on the data bus following the falling edge of both $\overline{\mathrm{CS}}$ and $\overline{\mathrm{RD}} . \overline{\mathrm{CS}}$ and $\overline{\mathrm{RD}}$ are both connected to same AND gate on the input so the signals are interchangeable. $\overline{\mathrm{CS}}$ and $\overline{\mathrm{RD}}$ can be hardwired permanently low in which case, the data bus is always active and the result of the new conversion are clocked out subsequent to the BU SY line going low. |
| $\overline{\text { CONVST }}$ | Conversion Start Input. Logic Input used to initiate conversion. The input track/hold amplifier goes from track mode to hold mode on the falling edge of CONVST and the conversion process is initi ated at this point. The conversion input can be as narrow as 15 ns . If the $\overline{\text { CONVST }}$ input is kept low for the duration of conversion and is still low at the end of conversion, the part will automatically enter a shutdown mode. If the part enters this shutdown mode, the next rising edge of CONVST wakes the part up. Wake-up time for the part is typically $1 \mu \mathrm{~s}$. |
| CLK IN | $M$ aster Clock Input. The clock source for the conversion process is applied to this pin. Conversion time for the AD 7472 takes 14 full clock cycles while conversion time for the AD 7470 takes 12 full clock cycles. The frequency of this master clock input therefore determines the conversion time and achievable throughput rate. The frequency range for this clock input is from 1 kHz to 28 M Hz . |
| BUSY | BU SY Output. Logic Output indicating the status of the conversion process. The BU SY signal goes high from the falling edge of $\overline{\text { CONVST }}$ and stays high for the duration of conversion. Once conversion is complete and the conversion result is in the output register, the BU SY line returns low. The track/hold returns to track mode prior to the falling edge of BUSY and the acquisition time for the part begins at this point. If the $\overline{\text { CONVST }}$ input is still low when BU SY goes low, the part automatically enters its shutdown mode on the falling edge of BUSY. |
| REF IN | Reference Input. An external reference must be applied to this input. T he voltage range for the external reference is $2.5 \mathrm{~V} \pm 1 \%$ for specified performance. |
| $A V_{\text {D }}$ | A nalog Supply Voltage, +2.7 V to +5.25 V . This is the only supply voltage for all analog circuitry on the $A D 7470 / 72$. $T$ he $A V_{D D}$ and $D V_{D D}$ voltages should ideally be at the same potential and must not be more than 0.3 V apart even on a transient basis. This supply should be decoupled to AGND. |
| $D V_{\text {D }}$ | Digital Supply Voltage, +2.7 V to +5.25 V . This is the supply voltage for all digital circuitry on the AD 7470/72 apart from the output drivers. The DV $V_{D D}$ and $A V_{D D}$ voltages should ideally be at the same potential and must not be more than 0.3 V apart even on a transient basis. T his supply should be decoupled to DGND. |
| AGND | A nalog $G$ round. Ground reference point for all analog circuitry on the AD 7470/72. All analog input signals and any external reference signal should be referred to this AGND voltage. The AGND and DGND voltages should ideally be at the same potential and must not be more than 0.3 V apart even on a transient basis. |
| DGND | Digital Ground. This is the ground reference point for all digital circuitry on the AD 7470/AD 7472. The DGND and AGND voltages should ideally be at the same potential and must not be more than 0.3 V apart even on a transient basis. |
| $\mathrm{V}_{\text {IN }}$ | A nalog Input. Single-ended analog input channel. The input range is OV to REFIN. The analog input presents a high dc input impedance. |
| $V_{\text {drive }}$ | Supply Voltage for the 0 utput Drivers, +2.7 V to +5.25 V . This voltage determines the output high voltage for the data output pins. It allows the AVDD and DVDD to operate at 5 V (and maximize the input signal if required) while the digital outputs can interface to 3 V logic. |
| DB0-D B9/11 | D ata Bit 0 to D ata Bit 9 (AD7470) and DB11 (AD7472). Parallel digital outputs which provide the conversion result for the part. These are three state outputs which are controlled by $\overline{\mathrm{CS}}$ and $\overline{\mathrm{RD}}$. The output high voltage level for these outputs is determined by the $\mathrm{V}_{\text {DRIVE }}$ input. |

## TERMINOLOGY <br> Integral Nonlinearity

This is the maximum deviation from a straight line passing through the endpoints of the ADC transfer function. The endpoints of the transfer function are zero scale, a point $1 / 2$ LSB below the first code transition, and full scale, a point 1/2 LSB above the last code transition.

## Differential Nonlinearity

This is the difference between the measured and the ideal 1 LSB change between any two adjacent codes in the ADC.

## Offset Error

This is the deviation of the first code transition (00 . . . 000)
to (00 . . . 001) from the ideal, i.e AGND + 1LSB

## Gain Error

The last transition should occur at the analog value 1 1/2 LSB below the nominal full scale. The first transition is a $1 / 2$ LSB above the low end of the scale (zero in the case of AD 7470/74). The gain error is the deviation of the actual difference between the first and last code transitions from the ideal difference between the first and last code transitions.

## Track/Hold Acquisition Time

The track/hold amplifier returns into track mode after the end of conversion. Track/H old acquisition time is the time required for the output of the track/hold amplifier to reach its final value, within $\pm 1 / 2$ LSB, after the end of conversion.

## Signal to (Noise + Distortion) Ratio

This is the measured ratio of signal to (noise + distortion) at the output of the A/D converter. The signal is the rms amplitude of the fundamental. N oise is the sum of all nonfundamental signals up to half the sampling frequency ( $\mathrm{f}_{\mathrm{s}}$ ) $2)$, excluding dc. The ratio is dependent on the number of quantization levels in the digitization process; the more levels, the smaller the quantization noise. The theoretical signal to (noise + distortion) ratio for an ideal N -bit converter with a sine wave input is given by:
Signal to $(\mathrm{N}$ oise + Distortion $)=(6.02 \mathrm{~N}+1.76) \mathrm{dB}$
Thus for a 12-bit converter, this is 74 dB and for a 10-bit converter is 62 dB .

## Total Harmonic Distortion

Total harmonic distortion (THD) is the ratio of the rms sum of harmonics to the fundamental. For the AD 7470/72, it is defined as:

$$
\mathrm{THD}(\mathrm{~dB})=20 \log \frac{\sqrt{\mathrm{~V}_{2}^{2}+\mathrm{V}_{3}^{2}+\mathrm{V}_{4}^{2}+\mathrm{V}_{5}^{2}+\mathrm{V}_{6}^{2}}}{\mathrm{~V}_{1}}
$$

where $\mathrm{V}_{1}$ is the rms amplitude of the fundamental and $\mathrm{V}_{2}$, $V_{3}, V_{4}, V_{5}$ and $V_{6}$ are the rms amplitudes of the second through the sixth harmonics.

## Peak Harmonic or Spurious Noise

Peak harmonic or spurious noise is defined as the ratio of the rms value of the next largest component in the ADC output spectrum (up to $\mathrm{f}_{\mathrm{s}} / 2$ and excluding dc ) to the rms value of the fundamental. N ormally, the value of this specification is determined by the largest harmonic in the spectrum, but for ADC s where the harmonics are buried in the noise floor, it will be a noise peak.

## Intermodulation Distortion

With inputs consisting of sine waves at two frequencies, fa and fb, any active device with nonlinearities will create distortion products at sum and difference frequencies of $\mathrm{mfa} \pm \mathrm{nfb}$ where $\mathrm{m}, \mathrm{n}=0,1,2,3$, etc. Intermodulation distortion terms are those for which neither $m$ nor $n$ are equal to zero. F or example, the second order terms include ( $\mathrm{fa}+\mathrm{fb}$ ) and ( $\mathrm{fa}-\mathrm{fb}$ ), while the third order terms include $(2 f a+f b)$, $(2 f a-f b)$, $(f a+2 f b)$ and (fa - 2fb).
The AD 7470/72 are tested using the CCIF standard where two input frequencies near the top end of the input bandwidth are used. In this case, the second order terms are usually distanced in frequency from the original sine waves while the third order terms are usually at a frequency close to the input frequencies. As a result, the second and third order terms are specified separately. The calculation of the intermodulation distortion is as per the THD specification where it is the ratio of the rms sum of the individual distortion products to the rms amplitude of the sum of the fundamentals expressed in dBs .

## PSR (Power Supply Rejection)

Variations in power supply will affect the full-scale transition, but not the conveter's linearity. Power Supply Rejection is the maximum change in the full-scale transition point due to a change in power-supply voltage from the nominal value.

## OUTLINE DIMENSIONS

Dimensions shown in inches and (mm).

24-LEAD SOIC (R-24)


24-LEAD TSSOP (RU-24)


## ADENDUM

Samples whose brand include the date code "9830" and "9838" on line 2, have an identified metastability problem which results in one conversion in approx. 1.2million giving an incorrect result.

This problem has been corrected on subsequent parts.


[^0]:    One Technology Way, P.O. Box 9106, Norwood, MA 02062-9106, U.S.A. Tel: 781/329-4700 World Wide Web Site: http:// www.analog.com Fax: 781/326-8703

    Analog Devices, Inc., 1998

